



BSI Standards Publication

**Nanotechnologies — Matrix of properties and measurement techniques for graphene and related two-dimensional (2D) materials**

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## National foreword

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**Nanotechnologies — Matrix of  
properties and measurement  
techniques for graphene and related  
two-dimensional (2D) materials**

*Nanotechnologies — Matrice des propriétés et des techniques de  
mesure pour le graphène et autres matériaux bidimensionnels (2D)*



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## Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see [www.iso.org/patents](http://www.iso.org/patents)).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see [www.iso.org/iso/foreword.html](http://www.iso.org/iso/foreword.html).

This document was prepared jointly by Technical Committee ISO/TC 229, *Nanotechnologies* and Technical Committee IEC/TC 113, *Nanotechnology for electrotechnical products and systems*. The draft was circulated for voting to the national bodies of both ISO and IEC.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at [www.iso.org/members.html](http://www.iso.org/members.html).

## Introduction

Graphene is a single layer of carbon atoms with each atom bound to three neighbours in a honeycomb structure<sup>[1]</sup>. Since its discovery in 2004<sup>[2]</sup>, graphene has become one of the most attractive materials in application research and device industry due to its supreme material properties such as mechanical strength, stiffness and elasticity, high electrical and thermal conductivity, optical transparency, etc. It is expected that applications of graphene could replace many of current device development technology in flexible touch panel, organic light emitting diode (OLED), solar cell, supercapacitor, and electromagnetic shielding. To gain deeper understanding of the material properties and to find the ways of mass producing with fine quality, much research on graphene, and similarly on related two-dimensional (2D) materials is being done in universities, research institutes, and laboratories around the globe. However, to lead these revolutionary materials to full commercialization, it is essentially demanded that characterization and measurement techniques for important material properties need to be standardized and globally recognized. In this document, characterization and measurement techniques for particular properties of graphene and related 2D materials which need to be standardized are organized in a form of a matrix. The matrix could serve as an initial guide for developing the necessary international standards in characterization and measurements of graphene and related 2D materials.

# Nanotechnologies — Matrix of properties and measurement techniques for graphene and related two-dimensional (2D) materials

## 1 Scope

This document provides a matrix which links key properties of graphene and related two-dimensional (2D) materials to commercially available measurement techniques. The matrix includes measurement techniques to characterize chemical, physical, electrical, optical, thermal and mechanical properties of graphene and related 2D materials.

## 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO/TS 80004-13, *Nanotechnologies — Vocabulary — Part 13: Graphene and related two-dimensional (2D) materials*

## 3 Terms and definitions, symbols and abbreviated terms

### 3.1 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO/TS 80004-13 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform, available at <https://www.iso.org/obp>
- IEC Electropedia: available at <http://www.electropedia.org/>

#### 3.1.1

##### **graphene**

single layer of carbon atoms with each atom bound to three neighbours in a honeycomb structure

Note 1 to entry: It is an important building block of many carbon nano-objects.

Note 2 to entry: As graphene is a single layer, it is also sometimes called monolayer graphene or single-layer graphene and abbreviated as 1LG to distinguish it from bilayer graphene (2LG) and few-layered graphene (FLG).

Note 3 to entry: Graphene has edges and can have defects and grain boundaries where the bonding is disrupted.

[SOURCE: ISO/TS 80004-13:2017, 3.1.2.1]